Search Notes

_	Application/Control No.	Applicant(s)/Patent un Reexamination	der
	09/758,836	MURAKAMI ET AL.	
	Examiner	Art Unit	
	Nam V. Nguyen	2612	

SEARCHED				
Class	Subclass	Date	Examiner	
340	5.82	3/20/2007	NN	
340	5.8-5.84	3/20/2007	NN	
340	5.52-5.53	3/20/2007	NN	
382	124	3/20/2007	NN	
382	115	3/20/2007	NN	
235	380	3/20/2007	NN	
235	492	3/20/2007	NN	
235	379	3/20/2007	NN	
235	381	3/20/2007	NN	
455	411	3/20/2007	NN	

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	I.				

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Seach East: USPAT; US-PUB; EPO; JPO; and Derwent.	3/20/2007	NN
Search Terms: biometric sensors; ic/credit card; reflected signal/wave with biometric sensors with smart card; portable dev.	3/20/2007	NN